

#### N-CHANNEL ENHANCEMENT MODE MOSFET PLUS NPN TRANSISTOR

#### **Features**

- N-Channel MOSFET and NPN Transistor in One Package
- Low On-Resistance
- Very Low Gate Threshold Voltage, 1.0V max
- Low Input Capacitance
- Fast Switching Speed
- Low Input/Output Leakage
- Ultra-Small Surface Mount Package
- ESD Protected MOSFET Gate up to 2kV
- Lead, Halogen and Antimony Free, RoHS Compliant (Note 1)
- "Green" Device (Note 2)
- Qualified to AEC-Q101 Standards for High Reliability

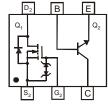
### **Mechanical Data**

- Case: SOT563
- Case Material: Molded Plastic, "Green" Molding Compound. UL Flammability Classification Rating 94V-0
- Moisture Sensitivity: Level 1 per J-STD-020
- Terminal Connections: See Diagram
- Terminals: Finish Matte Tin annealed over Copper lead frame.
  Solderable per MIL-STD-202, Method 208
- Weight: 0.006 grams (approximate)









Top View

**Bottom View** 

Top View Internal Schematic

### Ordering Information (Note 3)

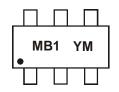
Part Number	Case	Packaging
DMB53D0UV-7	SOT563	3000/Tape & Reel
DMB53D0UV-13	SOT563	10000/Tape & Reel

**SOT563** 

Notes:

- 1. EU Directive 2002/95/EC (RoHS) & 2011/65/EU (RoHS 2) compliant. No purposely added lead. Halogen and Antimony free
- 2. Diodes Inc.'s "Green" policy can be found on our website at http://www.diodes.com.
- 3. For packaging details, go to our website at http://www.diodes.com.

## **Marking Information**



MB1 = Marking Code YM = Date Code Marking Y = Year (ex: V = 2008) M = Month (ex: 9 = September)

Date Code Key

Year	2008	2009	20	10	2011	2012	2013	2014	20	15	2016	2017
Code	V	W	>	X	Υ	Z	Α	В	(	C	D	E
Month	Jan	Feb	Mar	Apr	May	Jun	Jul	Aug	Sep	Oct	Nov	Dec
Code	1	2	3	4	5	6	7	8	9	0	N	D



## Maximum Ratings – MOSFET, Q1 @T<sub>A</sub> = 25°C unless otherwise specified

Character	istic	Symbol	Value	Units
Drain-Source Voltage		V <sub>DSS</sub>	50	V
Gate-Source Voltage		V <sub>GSS</sub>	±12	V
Drain Current (Note 4)	Continuous	I <sub>D</sub>	160	mA
Pulsed Drain Current (Note 4)		I <sub>DM</sub>	560	mA

## Maximum Ratings - NPN Transistor, Q2 @TA = 25°C unless otherwise specified

Characteristic	Symbol	Value	Unit
Collector-Base Voltage	$V_{CBO}$	50	V
Collector-Emitter Voltage	$V_{\sf CEO}$	45	V
Emitter-Base Voltage	$V_{EBO}$	6.0	V
Collector Current	Ι <sub>C</sub>	100	mA

### Thermal Characteristics, Total Device @TA = 25°C unless otherwise specified

Characteristic	Symbol	Value	Unit
Total Power Dissipation (Note 1)	$P_D$	250	mW
Thermal Resistance, Junction to Ambient (Note 1)	$R_{ hetaJA}$	500	°C/W
Operating and Storage Temperature Range	$T_{J}, T_{STG}$	-55 to +150	°C

## Electrical Characteristics - MOSFET @TA = 25°C unless otherwise specified

Characteristic	Symbol	Min	Тур	Max	Unit	Test Condition	
OFF CHARACTERISTICS (Note 5)							
Drain-Source Breakdown Voltage	BV <sub>DSS</sub>	50	_	_	V	$V_{GS} = 0V, I_D = 250\mu A$	
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	_	_	10	μΑ	$V_{DS} = 50V, V_{GS} = 0V$	
Gate-Body Leakage	I <sub>GSS</sub>	_	_	1.0 5.0	μА	$V_{GS} = \pm 8V, V_{DS} = 0V$ $V_{GS} = \pm 12V, V_{DS} = 0V$	
ON CHARACTERISTICS (Note 5)					-		
Gate Threshold Voltage	V <sub>GS(th)</sub>	0.7	0.8	1.0	V	$V_{DS} = V_{GS}, I_D = 250 \mu A$	
Static Drain-Source On-Resistance	D	_	3.1	4	Ω	$V_{GS} = 4V, I_D = 100mA$	
Static Diam-Source On-Resistance	R <sub>DS</sub> (ON)	_	4	5		$V_{GS} = 2.5V, I_D = 80mA$	
Forward Transconductance	g <sub>FS</sub>	180	_	_	mS	$V_{DS} = 10V, I_D = 100mA,$ f = 1.0KHz	
DYNAMIC CHARACTERISTICS (Note 6)	DYNAMIC CHARACTERISTICS (Note 6)						
Input Capacitance	C <sub>iss</sub>	_	25		pF	101/11/	
Output Capacitance	Coss		5	_	pF	$V_{DS} = 10V, V_{GS} = 0V,$ -f = 1.0MHz	
Reverse Transfer Capacitance	C <sub>rss</sub>	_	2.1		pF	T = 1.0IVII IZ	

Notes: 4. Device mounted on FR-4 substrate PC board, 2oz copper, with minimum recommended pad layout.

<sup>5.</sup> Short duration pulse test used to minimize self-heating effect.

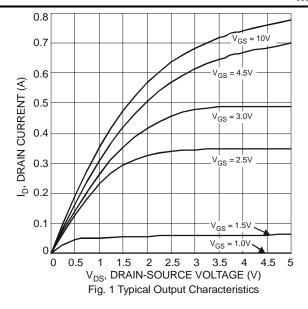
<sup>6.</sup> Guaranteed by design. Not subject to product testing.

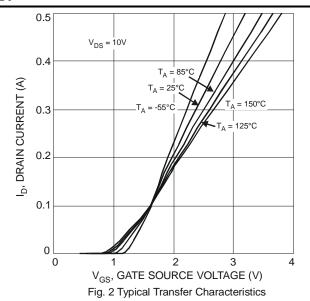


## Electrical Characteristics - NPN Transistor @TA = 25°C unless otherwise specified

Characteristic		Symbol	Min	Тур	Max	Unit	Test Condition
Collector-Base Breakdown Voltage	(Note 5)	V <sub>(BR)CBO</sub>	50	1	—	V	$I_C = 10\mu A, I_B = 0$
Collector-Emitter Breakdown Voltage	(Note 5)	V <sub>(BR)CEO</sub>	45	_	_	V	$I_C = 10 \text{mA}, I_B = 0$
Emitter-Base Breakdown Voltage	(Note 5)	V <sub>(BR)EBO</sub>	6	_	_	V	$I_E = 1 \mu A, I_C = 0$
DC Current Gain	(Note 5)	h <sub>FE</sub>	200	290	450	_	$V_{CE} = 5.0V, I_{C} = 2.0mA$
Collector-Emitter Saturation Voltage	(Note 5)	V <sub>CE(SAT)</sub>			100 300	mV	$I_C = 10$ mA, $I_B = 0.5$ mA $I_C = 100$ mA, $I_B = 5.0$ mA
Base-Emitter Saturation Voltage	(Note 5)	V <sub>BE(SAT)</sub>		700 900		mV	$I_C = 10 \text{mA}, I_B = 0.5 \text{mA}$ $I_C = 100 \text{mA}, I_B = 5.0 \text{mA}$
Base-Emitter Voltage	(Note 5)	$V_{BE}$	580 —	660 —	700 770	mV	$V_{CE} = 5.0V, I_{C} = 2.0mA$ $V_{CE} = 5.0V, I_{C} = 10mA$
Collector-Cutoff Current	(Note 5)	I <sub>CBO</sub>	_	_	15 5.0	nΑ μΑ	V <sub>CB</sub> = 30V V <sub>CB</sub> = 30V, T <sub>A</sub> = 150°C
Collector-Emitter Cut-Off Current	(Note 5)	I <sub>CES</sub>	_	_	100	nA	V <sub>CE</sub> = 45V
Gain Bandwidth Product		f <sub>T</sub>	100	_	_	MHz	$V_{CE} = 5.0V, I_{C} = 10mA,$ f = 100MHz
Output Capacitance		C <sub>OBO</sub>		_	4.5	pF	V <sub>CB</sub> = 10V, f = 1.0MHz
Noise Figure		NF	_	_	10	dB	$V_{CE} = 5V$ , $R_S = 2.0k\Omega$ , f = 1.0kHz, $BW = 200Hz$

#### **MOSFET**







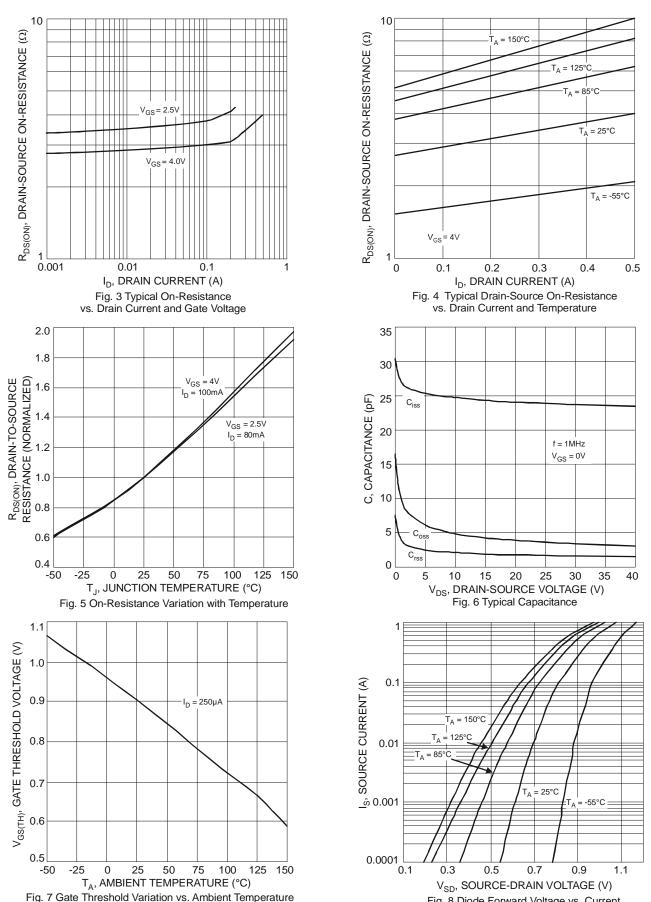


Fig. 8 Diode Forward Voltage vs. Current



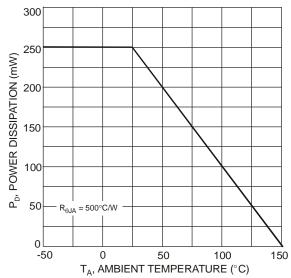


Fig. 9 Derating Curve - Total Package Power Dissipation

#### **NPN Transistor**

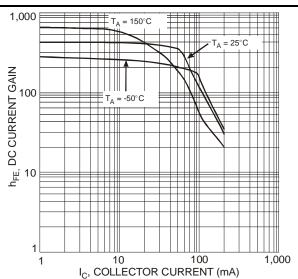


Fig. 10 Typical DC Current Gain vs. Collector Current

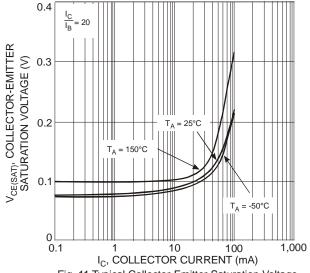


Fig. 11 Typical Collector-Emitter Saturation Voltage vs. Collector Current

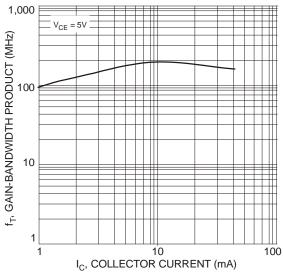
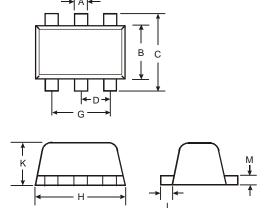


Fig. 12 Typical Gain-Bandwidth Product vs. Collector Current

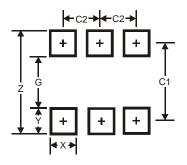


# **Package Outline Dimensions**



SOT563							
Dim	Min	Max	Тур				
Α	0.15	0.30	0.20				
В	1.10	1.25	1.20				
С	1.55	1.70	1.60				
D	-	-	0.50				
G	0.90	1.10	1.00				
Η	1.50	1.70	1.60				
K	0.55	0.60	0.60				
L	0.10	0.30	0.20				
M	0.10	0.18	0.11				
All	All Dimensions in mm						

# **Suggested Pad Layout**



Dimensions	Value (in mm)
Z	2.2
G	1.2
Х	0.375
Y	0.5
C1	1.7
C2	0.5



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